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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of

Yehiel Gotkis

Application No. 10/810,209

Filed: March 26, 2004

For: METHOD AND APPARATUS FOR

MEASUREMENT OF THIN FILMS AND RESIDUES

ON SEMICONDUCTOR SUBSTRATES

)
Examiner: Unassigned
)
Art Unit: 1765
)
Docket No. LAM2P466
)
Date: September 1, 2005
)

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on September 1, 2005.

Signed:

Kay Harlow

**INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR §§1.56 AND 1.97(e)**

Commissioner of Patents and Trademarks
Alexandria, VA 22313-1450

Dear Sir:

Enclosed is a PTO Form 1449 listing U.S. patents and foreign patents to be made of record. Applicant is hereby submitting a copy of the cited foreign patent. The references listed in the attached PTO Form 1449 may be material to examination of the above-identified patent application. The Examiner is requested to make these citations of official record in this application.

The undersigned hereby certifies that these references were cited in a Search Report from a foreign patent office less than three months before the filing date of the present Information Disclosure Statement. A copy of the Search Report is enclosed herewith. Accordingly, it is respectfully submitted that no fee is due in conjunction with the filing of this IDS.

This Information Disclosure Statement is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that these references indeed constitute prior art.

If the Commissioner should determine that additional fees are required for filing the present Information Disclosure Statement, the Commissioner is hereby authorized to charge any such fees to our deposit account number 50-0805 (Order No. LAM2P466). A copy of this sheet is enclosed.

Respectfully submitted,
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Attorney Docket No. LAM2P466



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Form 1449 (Modified)		Attorney Docket No:	U.S.
		LAM2P466	10/810,209
Information Disclosure Statement By Applicant		Applicant:	
		Y. Gotkis	
(Use Several Sheets if Necessary)		Filing Date:	Group:
		March 26, 2004	1765

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class
	A	US 2002/0054290 A1	05/2002	Vurens et al.	356	369
	B	5,898,181	04/1999	Vurens	250	559.28
	C					
	D					
	E					
	F					
	G					
	H					
	I					

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J	2000028748 <i>Patent Abstracts of Japan</i>	28/01/00	EPO	G01V	8/12		X
	K	WO 00/12958	09/03/00	WIPO	G01B	9/02		X
	L	0 296 365 A1	28/12/88	EPO	G01T	1/29		X
	M	WO 99/08066	18/02/99	WIPO	G01B	9/02		X
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	O	
	P	
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant.